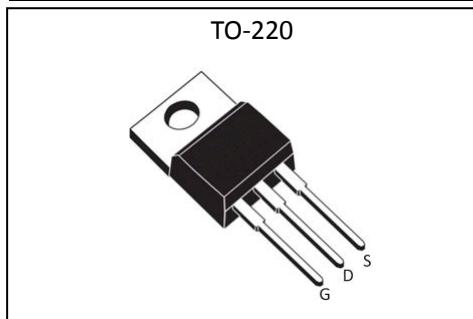


**Silicon N-Channel Power MOSFET**
**General Description:**

The HMB100N20 uses advanced trench technology and design to provide excellent RDS(ON) with low gate charge. It can be used in a wide variety of applications. The package form is TO-263, which accords with the RoHS standard.

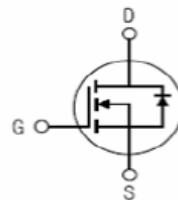
$V_{DSS}$	200	V
$I_D$	100	A
$P_D$	300	W
$R_{DS(ON)}\text{type}$	10	$\text{m}\Omega$


**Features:**

- Fast Switching
- Low Gate Charge and Rdson
- Low Reverse transfer capacitances
- 100% Single Pulse avalanche energy Test

**Applications:**

Power switching application  
Hard switched and high frequency circuits  
Uninterruptible power supply

**Inner Equivalent Principium Chart**

**Absolute** ( $T_c = 25^\circ\text{C}$  unless otherwise specified):

Symbol	Parameter	Rating	Units
$V_{DSS}$	Drain-to-Source Voltage	200	V
$I_D$	Continuous Drain Current	100	A
	Continuous Drain Current $T_c = 100^\circ\text{C}$	71	A
$I_{DM}$	Pulsed Drain Current	400	A
$V_{GS}$	Gate-to-Source Voltage	$\pm 20$	V
$E_{AS} \text{ a2}$	Single Pulse Avalanche Energy	1200	mJ
$E_{AR} \text{ a1}$	Avalanche Energy ,Repetitive	80	mJ
$I_{AR} \text{ a1}$	Avalanche Current	100	A
$dv/dt \text{ a3}$	Peak Diode Recovery $dv/dt$	5.0	V/ns
$P_D$	Power Dissipation	300	W
$T_J, T_{stg}$	Operating Junction and Storage Temperature Range	175, -55 to 175	$^\circ\text{C}$
$T_L$	MaximumTemperature for Soldering	300	$^\circ\text{C}$

**Electrical Characteristics (T<sub>c</sub> = 25 °C unless otherwise specified):**

OFF Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
V <sub>DSS</sub>	Drain to Source Breakdown Voltage	V <sub>GS</sub> =0V, I <sub>D</sub> =250μA	200	--	--	V
Δ BV <sub>DSS</sub> / Δ T <sub>J</sub>	Bvdss Temperature Coefficient	I <sub>D</sub> =250μA, Reference 25°C	--	0.1	--	V/°C
I <sub>DSS</sub>	Drain to Source Leakage Current	V <sub>DS</sub> = 200V, V <sub>GS</sub> = 0V, T <sub>a</sub> = 25°C	--	--	1	μA
		V <sub>DS</sub> = 160V, V <sub>GS</sub> = 0V, T <sub>a</sub> = 125°C	--	--	250	
I <sub>GSS(F)</sub>	Gate to Source Forward Leakage	V <sub>GS</sub> = +20V	--	--	1	μA
I <sub>GSS(R)</sub>	Gate to Source Reverse Leakage	V <sub>GS</sub> = -20V	--	--	-1	μA

ON Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
R <sub>DS(ON)</sub>	Drain-to-Source On-Resistance	V <sub>GS</sub> =10V, I <sub>D</sub> =50A	--	10	14	mΩ
V <sub>GS(TH)</sub>	Gate Threshold Voltage	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250μA	2.5	--	4.5	V
Pulse width t <sub>p</sub> ≤ 380μs, δ ≤ 2%						

Dynamic Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
g <sub>fs</sub>	Forward Transconductance	V <sub>DS</sub> =10V, I <sub>D</sub> = 50A	70	--	--	S
C <sub>iss</sub>	Input Capacitance	V <sub>GS</sub> = 0V V <sub>DS</sub> = 100V f = 1.0MHz	--	4300	--	pF
C <sub>oss</sub>	Output Capacitance		--	350	--	
C <sub>rss</sub>	Reverse Transfer Capacitance		--	10	--	

Resistive Switching Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
t <sub>d(ON)</sub>	Turn-on Delay Time	I <sub>D</sub> = 50A V <sub>DD</sub> = 100V V <sub>GS</sub> = 10V R <sub>G</sub> = 4.7Ω	--	18	--	ns
tr	Rise Time		--	27	--	
t <sub>d(OFF)</sub>	Turn-Off Delay Time		--	42	--	
t <sub>f</sub>	Fall Time		--	12	--	
Q <sub>g</sub>	Total Gate Charge	I <sub>D</sub> = 50A V <sub>DD</sub> = 100V V <sub>GS</sub> = 10V	--	65	--	nC
Q <sub>gs</sub>	Gate to Source Charge		--	25	--	
Q <sub>gd</sub>	Gate to Drain ("Miller") Charge		--	17	--	

**Source-Drain Diode Characteristics**

Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
$I_s$	Continuous Source Current (Body Diode)		--	--	100	A
$I_{SM}$	Maximum Pulsed Current (Body Diode)		--	--	400	A
$V_{SD}$	Diode Forward Voltage	$I_s=100A, V_{GS}=0V$	--	--	1.5	V
$t_{rr}$	Reverse Recovery Time	$I_s=100A, T_j = 25^\circ C$	--	140	--	ns
$Q_{rr}$	Reverse Recovery Charge	$dI_F/dt=100A/\mu s, V_{GS}=0V$	--	600	--	nC
Pulse width $t_p \leq 380\mu s, \delta \leq 2\%$						

Symbol	Parameter	Typ.	Units
$R_{J-C}$	Junction-to-Case	0.5	°C/W

<sup>a1</sup>: Repetitive rating; pulse width limited by maximum junction temperature

<sup>a2</sup>: EAS condition :  $T_j=25^\circ C$ ,  $V_{DD}=50V, V_G=10V, L=0.5mH, R_g=25\Omega$

<sup>a3</sup>:  $I_{SD} = 100A, dI/dt \leq 100A/\mu s, V_{DD} \leq BV_{DS}$ , Start  $T_j=25^\circ C$

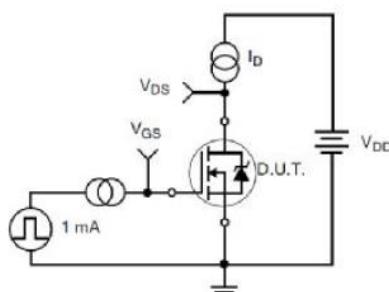
**Test Circuit and Waveform**


Figure 17. Gate Charge Test Circuit

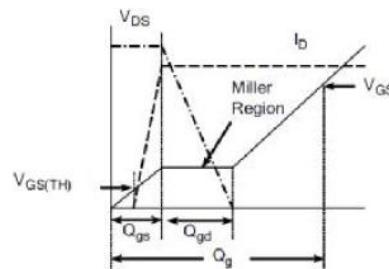


Figure 18. Gate Charge Waveform

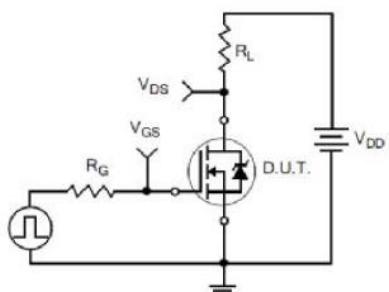


Figure 19. Resistive Switching Test Circuit

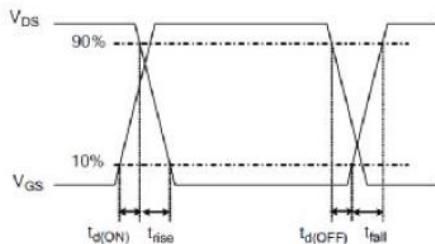
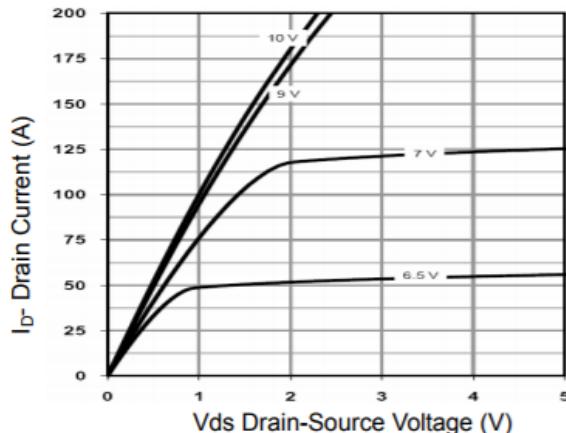
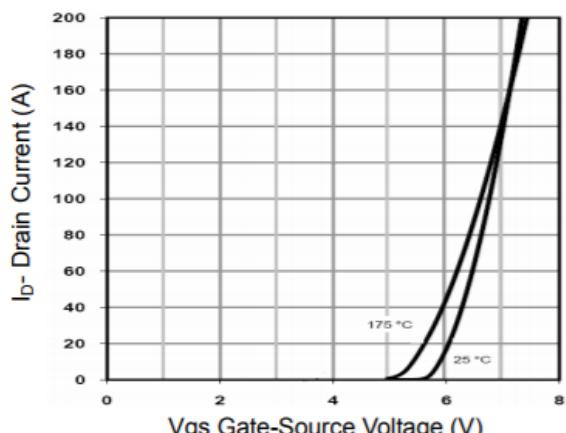
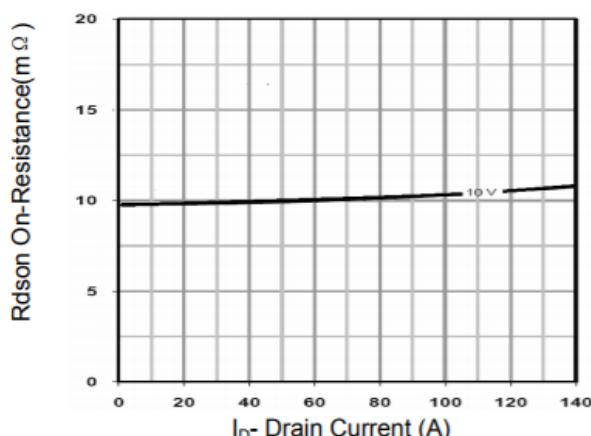
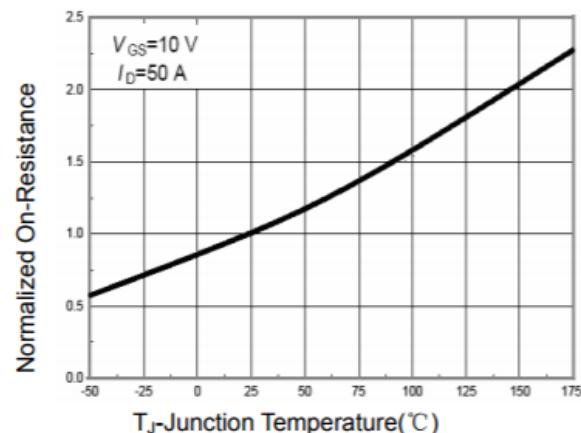
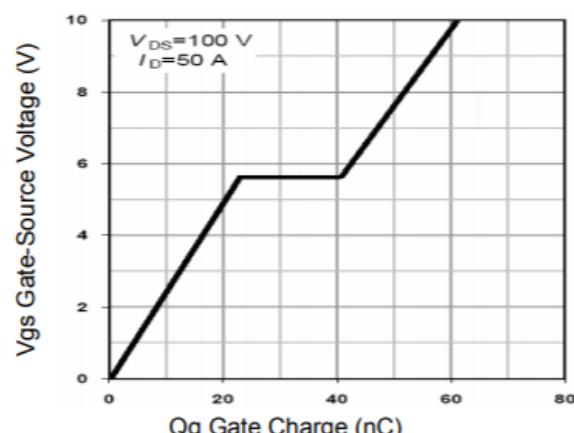
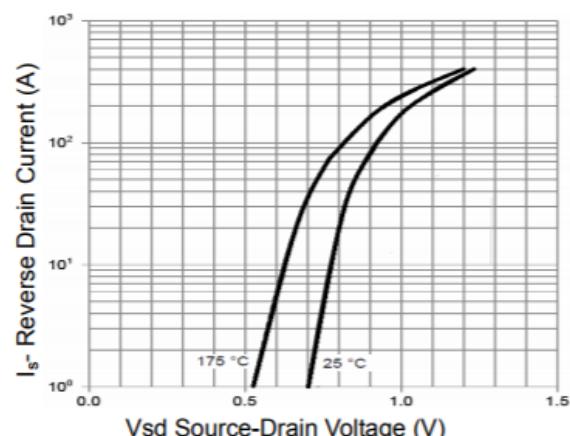
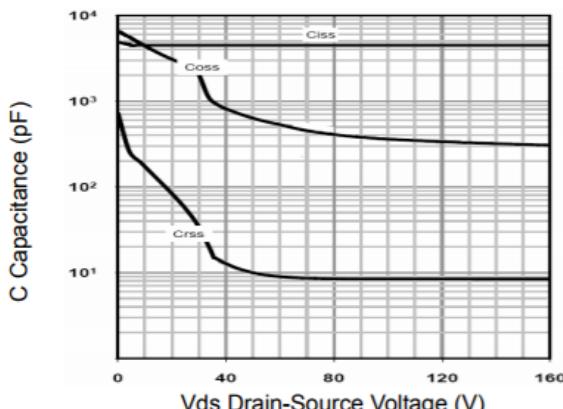
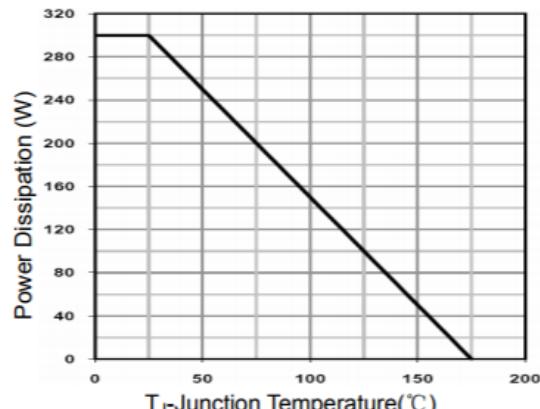


Figure 20. Resistive Switching Waveforms

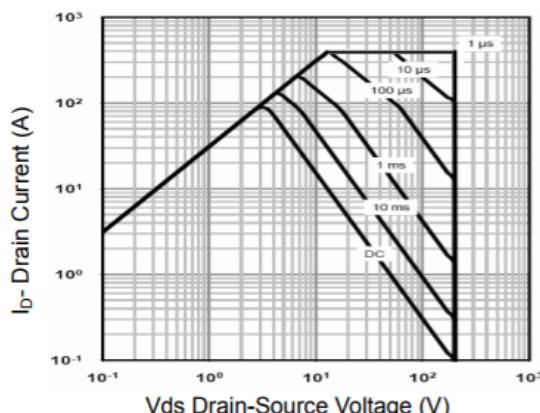
**Characteristics Curve :**

**Figure 1 Output Characteristics**

**Figure 2 Transfer Characteristics**

**Figure 3 Rdson- Drain Current**

**Figure 4 Rdson-JunctionTemperature**

**Figure 5 Gate Charge**

**Figure 6 Source- Drain Diode Forward**



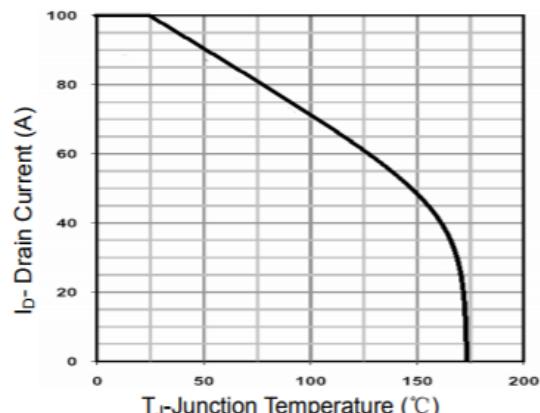
**Figure 7 Capacitance vs Vds**



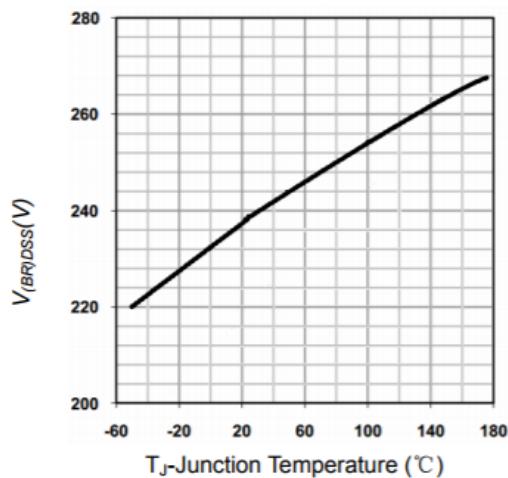
**Figure 9 Power De-rating**



**Figure 8 Safe Operation Area**



**Figure 10 Current De-rating**



**Figure 11 Drain-source breakdown voltage**